Se	arch Note	es

Application/Control No.	Applicant(s)/Patent under Reexamination
10/037,164	CHEN ET AL.
Examiner	Art Unit
Jennifer N. To	2195

	SEAR	CHED	
Class	Subclass	Date	Examiner
718	100-108	2/9/2006	JΤ
707	10	2/9/2006	JT
		-	

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

SEARCH NO (INCLUDING SEARCH		)
	DATE	EXMR
*		
INVENTOR NAME SEARCH	2/9/2006	JT
EAST UPDATE SEARCH	2/9/2006	JT